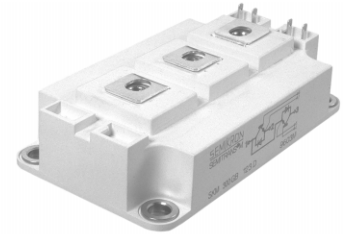
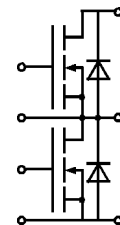


## SEMITRANS® M Power MOSFET Modules 250 A, 200 V, 8,6 mΩ

### SKM 253 B 020



SEMITRANS M3



#### Features

- N Channel, enhancement mode
- Short internal connections and low inductance case avoid oscillations
- Isolated copper baseplate using Al<sub>2</sub>O<sub>3</sub> ceramic Direct Copper Bonding Technology (DCB)
- All electrical connections on top for easy busbaring
- Large clearance (13 mm) and creepage distances (20 mm)
- UL recognized, file no. E63 532

#### Typical Applications

- DC servo and robot drives
- DC choppers
- UPS equipment
- Plasma cutting
- Not suitable for linear amplification

**This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.**

Suitable mounting hardware:  
Ident No. 33321100  
(for 10 SEMITRANS 3)  
Screws → B 6 – 4

Absolute Maximum Ratings		Values	Units
Symbol	Conditions <sup>1)</sup>		
V <sub>DS</sub>		200	V
V <sub>DGR</sub>	R <sub>GE</sub> = 20 kΩ	200	V
I <sub>D</sub>	T <sub>case</sub> = 25 °C	250	A
	T <sub>case</sub> = 100 °C	150	A
I <sub>DM</sub>	1 ms	750	A
V <sub>GS</sub>		± 20	V
P <sub>D</sub>		1000	W
T <sub>j</sub> , (T <sub>stg</sub> )		-40 ... +150 (125)	°C
V <sub>isol</sub>	AC, 1 min., 200 μA	2 500	V
humidity	DIN 40 040	Class F	
climate	DIN IEC 68 T.1	40/125/56	
Inverse Diode			
I <sub>F</sub> = -I <sub>D</sub>		250	A
I <sub>FM</sub> = -I <sub>DM</sub>	10 μs	1000	A

Characteristics		min.	typ.	max.	Units
Symbol	Conditions <sup>1)</sup>				
V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0, I <sub>D</sub> = 0,5 mA	200	–	–	V
V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 1 mA	2,1	3,0	4,0	V
I <sub>DSS</sub>	V <sub>GS</sub> = 0 } T <sub>j</sub> = 25 °C	–	–	125	μA
	V <sub>DS</sub> = 200 V } T <sub>j</sub> = 125 °C	–	–	1250	μA
I <sub>GSS</sub> <sup>3)</sup>	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0	–	–	100	nA
R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 150 A	–	8	8,6	mΩ
g <sub>fs</sub>	V <sub>DS</sub> = 25 V, I <sub>D</sub> = 150 A	–	200	–	S
C <sub>CHC</sub>		–	–	700	pF
C <sub>iss</sub>	} V <sub>GS</sub> = 0 } V <sub>DS</sub> = 25 V } f = 1 MHz	–	34	39	nF
C <sub>oss</sub>		–	6,5	7,5	nF
C <sub>rss</sub>		–	2,5	3,5	nF
L <sub>DS</sub>		–	–	20	nH
t <sub>d(on)</sub>	} V <sub>DD</sub> = 30 V } I <sub>D</sub> = 150 A } V <sub>GS</sub> = ± 10 V } R <sub>G</sub> = 4,7 Ω	–	100	–	ns
t <sub>r</sub>		–	100	–	ns
t <sub>d(off)</sub>		–	700	–	ns
t <sub>f</sub>		–	250	–	ns
Inverse Diode <sup>8)</sup>					
V <sub>SD</sub>	I <sub>F</sub> = 250 A, V <sub>GS</sub> = 0 V	–	–	1,5	V
t <sub>rr</sub>	T <sub>j</sub> = 25 °C <sup>3)</sup>	–	160	–	ns
	T <sub>j</sub> = 150 °C <sup>3)</sup>	–	–	–	ns
Q <sub>rr</sub>	T <sub>j</sub> = 25 °C <sup>3)</sup>	–	12	–	μC
I <sub>RR</sub>	T <sub>j</sub> = 150 °C <sup>3)</sup>	–	–	–	A
Thermal characteristics					
R <sub>thjc</sub>	per MOSFET	–	–	0,12	°C/W
R <sub>thch</sub>	M1, surface 10 μm, per module	–	–	0,038	°C/W

Mechanical Data						
M <sub>1</sub>	to heatsink, SI Units	(M6)	3	–	5	Nm
	to heatsink, US Units		27	–	44	lb.in.
M <sub>2</sub>	for terminals, SI Units	(M6)	2,5	–	5	Nm
	for terminals, US Units		22	–	44	lb.in.
a			–	–	5x9,81	m/s <sup>2</sup>
w			–	–	325	g
Case	→ B 5 – 42				D 56	

<sup>1)</sup> T<sub>case</sub> = 25 °C, unless otherwise specified

<sup>3)</sup> I<sub>F</sub> = 250 A, V<sub>R</sub> = 100 V, -di<sub>F</sub>/dt = 100 A/μs

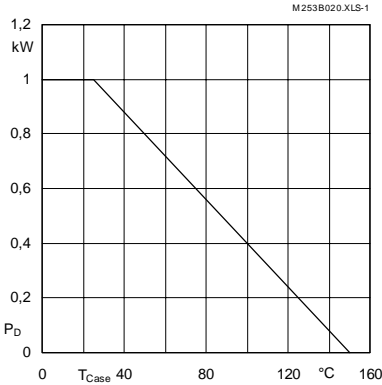


Fig. 1 Rated power dissipation vs. temperature

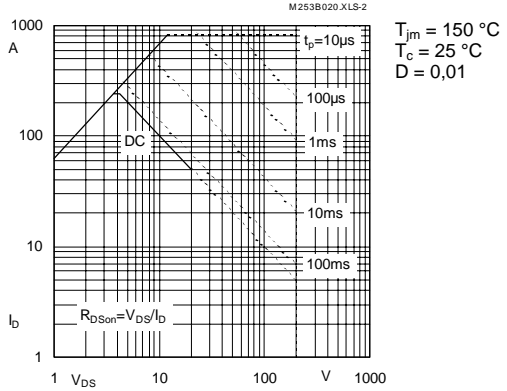


Fig. 2 Maximum safe operating area, single pulse

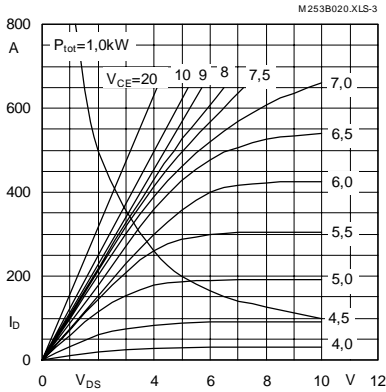


Fig. 3 Output characteristic,  $t_p = 80 \mu s$ ,  $T_j = 25 \text{ }^\circ\text{C}$

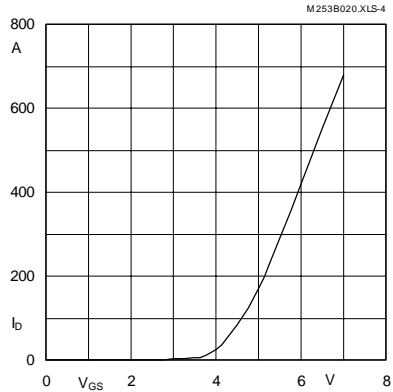


Fig. 4 Transfer characteristic,  $t_p = 80 \mu s$ ,  $V_{DS} = 25 \text{ V}$

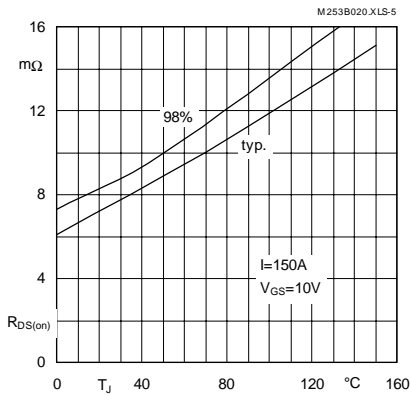


Fig. 5 On-resistance vs. temperature

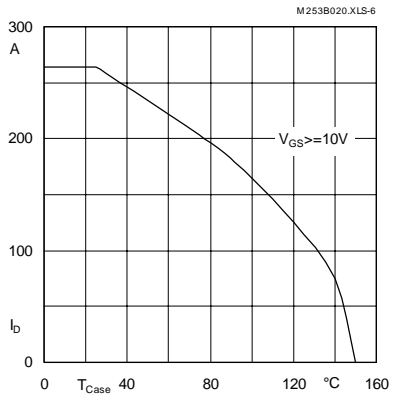


Fig. 6 Rated current vs. temperature

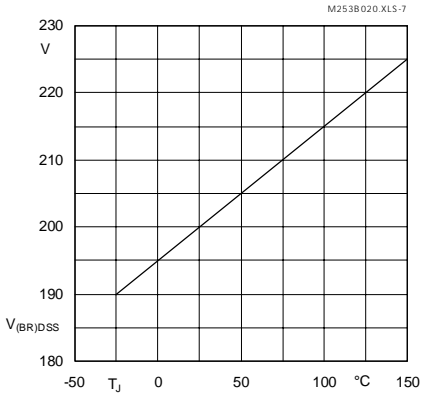


Fig. 7 Breakdown voltage vs. temperature

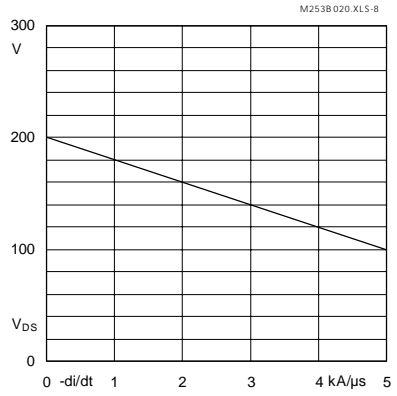


Fig. 8 Drain-source voltage derating ( $L_{DS}$ )

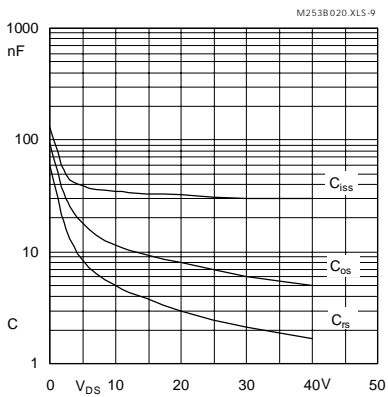


Fig. 9 Typ. capacitances vs. drain-source voltage

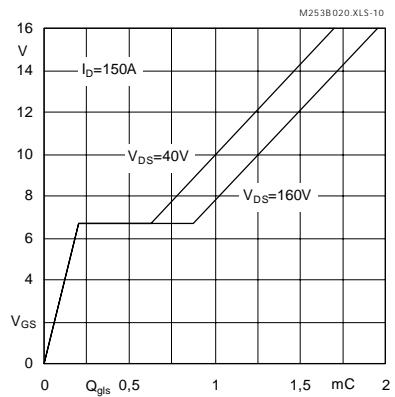


Fig. 10 Gate charge characteristic,  $I_{DP} = 250 \text{ A}$

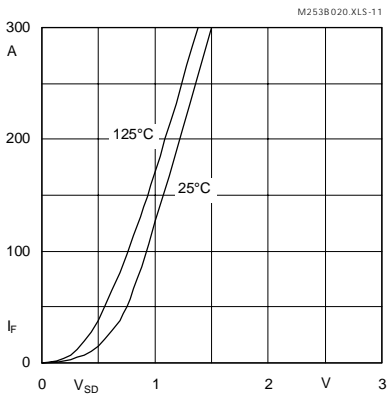


Fig. 11 Diode forward characteristic,  $t_p = 80 \mu\text{s}$

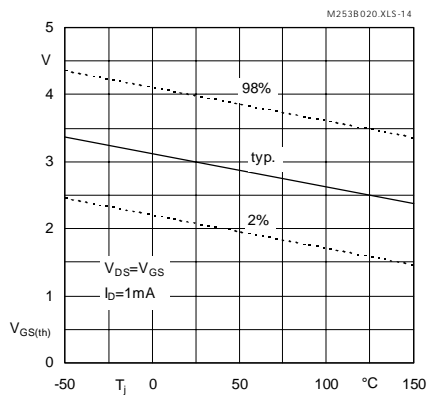


Fig. 14 Gate-source threshold voltage

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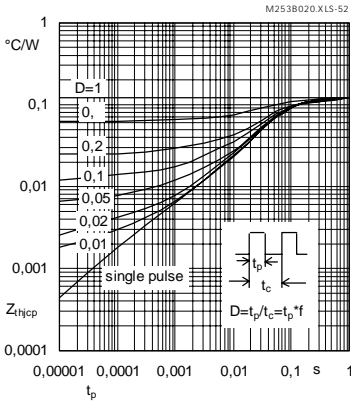


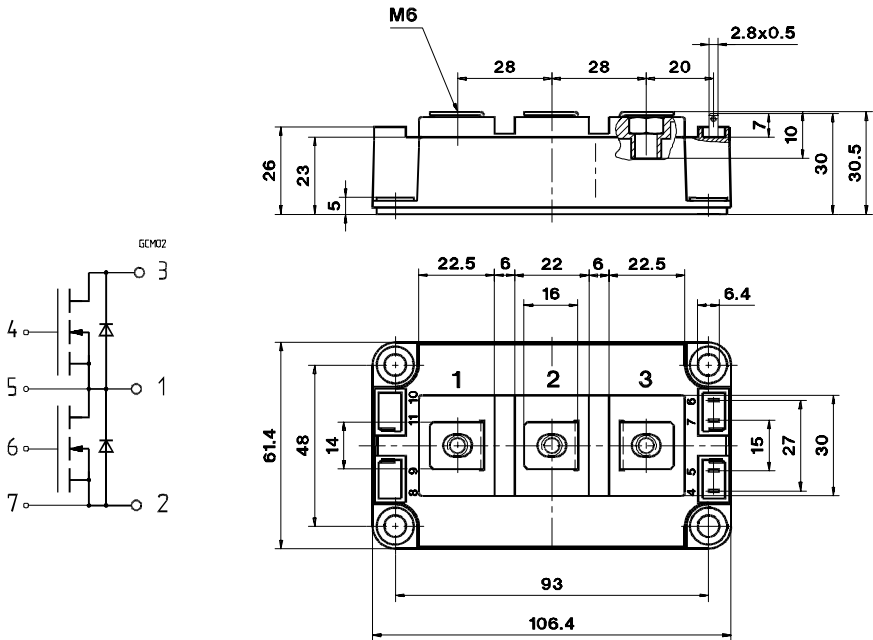
Fig. 52 Thermal impedance under pulse conditions

## SEMISTRANS M 3

Case D 56

## SKM 253 B 020

CASED56



Dimensions in mm